













TS5MP645

SCDS385B - JANUARY 2018 - REVISED JULY 2018

TS5MP645 4-Data Lane 2:1 MIPI Switch (10-Channel, 2:1 Analog Switch)

Features

- Supply Range of 1.65 V to 5.5 V
- 10-Channel 2:1 Switch
- Powered-Off Protection I/Os Hi-Z when $V_{DD} = 0 \text{ V}$
- Low R_{ON} of 2.45- Ω Typical
- Low Con of 1.5 pF
- Minimum bandwidth of 1.5 GHz
- Ultra Low Crosstalk of -40 dB
- Low Power Disable Mode
- 1.8-V Compatible Logic Inputs
- ESD Protection Exceeds JESD 22
 - 2000-V Human Body Model (HBM)

Applications

- Mobile Phones
- **Tablet**
- PC/Notebook
- Virtual Reality
- Augmented Reality

3 Description

The TS5MP645 is a four data lane MIPI switch. This device is an optimized 10 channel (5 differential) single-pole, double-throw switch for use in high speed applications. The TS5MP645 is designed to facilitate multiple MIPI compliant devices to connect to a single CSI/DSI, C-PHY/D-PHY module.

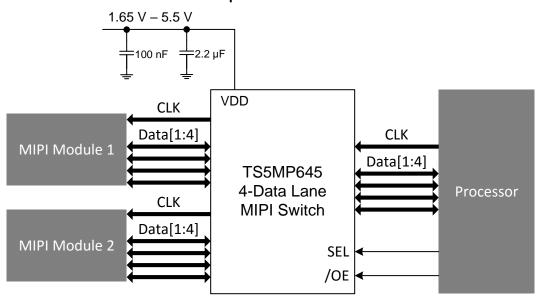
The device has excellent bandwidth, low channel to channel skew with little signal degradation, and wide margins to compensate for layout losses. The low current consumption meets the need of low power applications.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TS5MP645	DSBGA (YFP)	2.42 mm x 2.42 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic



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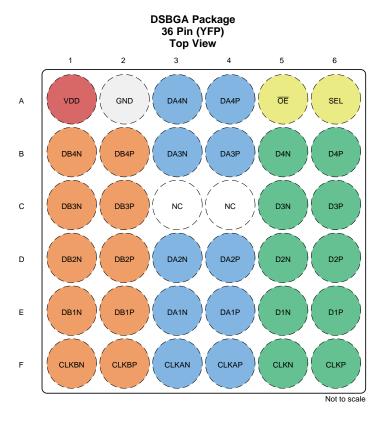
4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (March 2018) to Revision B Page Changed the I_{OFF} Test conditions From: V_{DD} = 1.65 V to 5.5 V To: V_{DD} = 0 V, 1.65 V to 5.5 V in the *Electrical Characteristics* table Changes from Original (January 2018) to Revision A Page Changed the BODY SIZE (NOM) in the Device Information table From: 2.459 x 2.459 To: 2.42 x 2.42



5 Pin Configuration and Functions



Pin Functions

Р	PIN		DESCRIPTION
NAME	NO.	I/O	DESCRIPTION
VDD	A1	PWR	Power supply input
GND	A2	GND	Device Ground
DA4N	А3	I/O	Differential I/O
DA4P	A4	I/O	Differential I/O
ŌĒ	A5	1	Output enable (Active Low)
SEL	A6	1	Channel Select
DB4N	B1	I/O	Differential I/O
DB4P	B2	I/O	Differential I/O
DA3N	В3	I/O	Differential I/O
DA3P	B4	I/O	Differential I/O
D4N	B5	I/O	Differential I/O
D4P	B6	I/O	Differential I/O
DB3N	C1	I/O	Differential I/O
DB3P	C2	I/O	Differential I/O
NC	С3	-	No connect
NC	C4	-	No connect
D3N	C5	I/O	Differential I/O
D3P	C6	I/O	Differential I/O
DB2N	D1	I/O	Differential I/O
DB2P	D2	I/O	Differential I/O
DA2N	D3	I/O	Differential I/O



Pin Functions (continued)

P	IN	1/0	DECODINE
NAME	NO.	I/O	DESCRIPTION
DA2P	D4	I/O	Differential I/O
D2N	D5	I/O	Differential I/O
D2P	D6	I/O	Differential I/O
DB1N	E1	I/O	Differential I/O
DB1P	E2	I/O	Differential I/O
DA1N	E3	I/O	Differential I/O
DA1P	E4	I/O	Differential I/O
D1N	E5	I/O	Differential I/O
D1P	E6	I/O	Differential I/O
CLKBN	F1	I/O	Differential I/O
CLKBP	F2	I/O	Differential I/O
CLKAN	F3	I/O	Differential I/O
CLKAP	F4	I/O	Differential I/O
CLKN	F5	I/O	Differential I/O
CLKP	F6	I/O	Differential I/O



6 Specifications

6.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
V_{DD}	Supply Voltage	-0.5	6	V
V _{I/O}	Analog voltage range (DxN, CLKN, DxP, CLKP, DAxN, CLKAN, DAxP, CLKAP, DBxN, CLKBN, DBxP, CLKBP)	-0.5	4	V
V_{SEL} , $V_{\overline{OE}}$	Digital Input Voltage (SEL, OE)	-0.5	6	V
TJ	Junction temperature	-65	150	°C
T _{stg}	Storage temperature	-65	150	°C

⁽¹⁾ Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage are with respect to ground, unless otherwise specified

6.2 ESD Ratings

			VALUE	UNIT
V	Flacticatetia diagharma	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	V
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±250	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

Over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V_{DD}	Supply Voltage	1.65	5.5	V
V _{I/O}	Analog voltage range (DxN, CLKN, DxP, CLKP, DAxN, CLKAN, DAxP, CLKAP, DBxN, CLKBN, DBxP, CLKBP)	0	3.6	V
$V_{SEL}, V_{\overline{OE}}$	Digital Input Voltage (SEL, OE)	0	5.5	V
I _{I/O}	Continuous I/O current	-35	35	mA
T _A	Operating ambient temperature	-40	85	°C
TJ	Junction temperature	-65	150	°C

6.4 Thermal Information

		TS5MP645	
	THERMAL METRIC ⁽¹⁾	YFP	UNIT
		36	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	57.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	0.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	12.6	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	0.2	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	12.7	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.5 Electrical Characteristics

Over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
POWER SUP	PLY					
I _{DD}	Active Supply Current	V _{DD} = 1.65 V to 5.5 V OE = 0 V SEL = 0 V to 5.5 V Dn, CLKn = 0 V	0	30	60	μΑ
I _{DD_PD}	Power-down Supply current	$V_{DD} = 1.65 \text{ V to } 5.5 \text{ V}$ $\overline{\text{OE}} = V_{DD}$ $\text{SEL} = 0 \text{ V to } 5.5 \text{ V}$ $\text{Dn, CLKn} = 0 \text{ V}$	0	0.1	1	μА
I _{DD_PD_1.8}	Power-down Supply current	VDD = 1.65 V to 5.5 V OE = 1.8 V SEL = 0 V to 5.5 V Dn, CLKn = 0 V	0	0.1	10	μΑ
DC CHARAC	TERISTICS					
R _{ON_HS}	On-state resistance	$V_{DD} = 1.65 \text{ V to } 5.5 \text{ V}$ $\overline{\text{OE}} = 0 \text{ V}$ Dn,CLKn = -8 mA, 0.2V DAn, DBn, CLKAn, CLKBn = 0.2 V, -8 mA		2.45	5.5	Ω
R _{ON_LP}	On-state resistance	V _{DD} = 1.65 V to 5.5 V OE = 0 V Dn, CLKn = -8 mA, 1.2V DAn, DBn, CLKAn, CLKBn = 1.2 V, -8 mA		2.65	6.5	Ω
R _{ON_flat_HS}	On-state resistance flatness	V _{DD} = 1.65 V to 5.5 V OE = 0 V Dn, CLKn = -8 mA, 0 V to 0.3 V DAn, DBn, CLKAn, CLKBn = 0 V to 0.3 V,-8 mA		0.1		Ω
R _{ON_flat_LP}	On-state resistance flatness	V _{DD} = 1.65 V to 5.5 V OE = 0 V Dn, CLKn = -8 mA, 0 V to 1.3 V DAn, DBn, CLKAn, CLKBn = 0 V to 1.3 V, -8 mA		0.9		Ω
Δ_{RON_HS}	On-state resistance match between+and - paths	V _{DD} = 1.65 V to 5.5 V OE = 0 V Dn, CLKn = -8 mA, 0.2 V DAn, DBn, CLKAn, CLKBn = 0.2 V, -8 mA		0.1		Ω
Δ_{RON_LP}	On-state resistance match between+and - paths	V_{DD} = 1.65 V to 5.5 V $\overline{\text{OE}}$ = 0 V Dn, CLKn = -8 mA, 1.2 V DAn, DBn, CLKAn, CLKBn = 1.2 V, -8 mA		0.1		Ω
l _{OFF}	Switch off leakage current	V _{DD} = 0 V, 1.65 V to 5.5 V OE = 0 V to 5.5 V SEL= 0 V to 5.5 V Dn, CLKn = 0 V to 1.3 V DAn, DBn, CLKAn, CLKBn = 0 V to 1.3 V	-0.5		0.5	μΑ
I _{ON}	Switch on leakage current	V _{DD} = 1.65 V to 5.5 V $\overline{\text{OE}}$ = 0 V SEL= 0 V to 5.5 V Dn, CLKn = 0 V to 1.3 V DAn, DBn, CLKAn, CLKBn = 0 V to 1.3 V	-0.5		0.5	μА
DYNAMIC CH	IARACTERISTICS					
t _{SWITCH}	Switching time between channels	$\begin{split} &V_{DD}=1.65 \text{ V to } 5.5 \text{ V} \\ \hline \text{OE} &= 0 \text{ V} \\ \\ \text{Dn, CLKn} &= 0.6 \text{ V} \\ \\ \text{DAn, DBn, CLKAn, CLKBn: } &R_L = 50 \ \Omega, \ C_L = 5 \text{ pF} \end{split}$			1.5	μs
f _{SEL_MAX}	Maximum toggling frequency for the SEL line	V_{DD} = 1.65 V to 5.5 V Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L =1 pF			100	kHz
t _{ON_OE}	Device enable time $\overline{\sf OE}$ to switch on	V_{DD} = 1.65 V to 5.5 V Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L = 1 pF		50	300	μs
t _{ON_VDD}	Device enable time V _{DD} to switch on	V_{DD} = 0 V to 1.65 V Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L = 1 pF		50	300	μs



Electrical Characteristics (continued)

Over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{OFF_OE}	Device disable time $\overline{\text{OE}}$ to switch off	V_{DD} = 1.65 V to 5.5 V Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L = 1 pF		0.5	1	μs
t _{OFF_VDD}	Device disable time V _{DD} to switch off	V_{DD} = 5 V to 0 V VDD ramp rate = 250 μs Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L = 1pF		0.5	1	ms
t _{MIN_OE}	Minimum pulse width for OE	V_{DD} = 1.65 V to 5.5 V Dn, CLKn = 0.6 V DAn, DBn, CLKAn, CLKBn: R_L = 50 Ω , C_L = 1 pF	500			ns
t _{BBM}	Break before make time	$\begin{aligned} & \frac{V_{DD}}{OE} = 1.65 \text{ V to } 5.5 \text{ V} \\ & \overline{OE} = 0 \text{ V} \\ & Dn, \text{ CLKn} = \text{R}_{\text{L}} = 50 \Omega, \text{ C}_{\text{L}} = 1 \text{ pF} \\ & DAn, \text{ DBn, CLKAn, CLKBn: } 0.6 \text{ V} \end{aligned}$	50			ns
t _{SKEW}	Intrapair skew	$\begin{aligned} & V_{DD} = 1.65 \text{ V to } 5.5 \text{ V} \\ & \overline{\text{OE}} = 0 \text{ V} \\ & \text{Dn, CLKn} = 0.3 \text{ V} \\ & \text{DAn, DBn, CLKAn, CLKBn: } R_{\text{L}} = 50 \Omega, C_{\text{L}} = 1 \text{ pF} \end{aligned}$		1		ps
t _{SKEW}	Interpair Skew	$\begin{split} & \frac{V_{DD}}{OE} = 1.65 \text{ V to } 5.5 \text{ V} \\ & \overline{OE} = 0 \text{ V} \\ & Dn, \text{ CLKn} = 0.3 \text{ V} \\ & DAn, \text{ DBn, CLKAn, CLKBn: } R_{L} = 50 \Omega, C_{L} = 1 \text{ pF} \end{split}$		4		ps
t _{PD}	Propagation delay with 100 ps rise time	$\begin{split} & \frac{V_{DD}}{OE} = 1.65 \text{ V to } 5.5 \text{ V} \\ & \overline{OE} = 0 \text{ V} \\ & Dn, \text{ CLKn} = 0.6 \text{ V} \\ & DAn, \text{ DBn, CLKAn, CLKBn: } R_L = 50 \ \Omega, C_L = 1 \text{ pF} \\ & t_{RISE} = 100 \text{ ps} \end{split}$		40		ps
O _{ISO}	Differential off isolation	$\begin{split} &\frac{V_{DD}}{OE} = 1.65 \text{ V} \\ &\overline{OE} = 0 \text{ V, } V_{DD} \\ &\text{SEL} = 0 \text{ V, } V_{DD} \\ &\text{Dn, CLKn, DAn, DBn, CLKAn, CLKBn: } R_S = 50 \ \Omega, \\ &R_L = 50 \ \Omega, \ C_L = 1 \text{ pF} \\ &V_{I/O} = 200 \text{ mV} + 200 \text{ mV}_{PP} \text{ (differential)} \\ &f = 1250 \text{ MHz} \end{split}$		-20		dB
X _{TALK}	Differential channel to channel crosstalk	$\begin{split} &V_{DD}=1.65 \text{ V to } 5.5 \text{ V} \\ \hline \text{OE} = 0 \text{ V, V}_{DD} \\ \text{SEL} = 0 \text{ V, V}_{DD} \\ \text{Dn, CLKn, DAn, DBn, CLKAn, CLKBn: R}_S = 50 \ \Omega, \\ &R_L = 50 \ \Omega, \ C_L = 1 \text{ pF} \\ &V_{I/O} = 200 \text{ mV} + 200 \text{ mV}_{PP} \text{ (differential)} \\ &f = 1250 \text{ MHz} \end{split}$		-40		dB
BW	Differential Bandwidth	$\begin{split} \frac{V_{DD}}{OE} &= 1.65 \text{ V to } 5.5 \text{ V} \\ \overline{OE} &= 0 \text{ V} \\ \text{SEL} &= 0 \text{ V, } V_{DD} \\ \text{Dn, CLKn, DAn, DBn, CLKAn, CLKBn: } R_S &= 50 \Omega, \\ R_L &= 50 \Omega, C_L &= 1 \text{ pF} \\ V_{I/O} &= 200 \text{ mV} + 200 \text{ mV}_{PP} \text{ (differential)} \end{split}$	1.5	2		GHz
I _{LOSS}	Insertion Loss	$\begin{split} \frac{V_{DD}}{OE} &= 1.65 \text{ V to } 5.5 \text{ V} \\ \overline{OE} &= 0 \text{ V} \\ \text{SEL} &= 0 \text{ V, V}_{DD} \\ \text{Dn, CLKn, DAn, DBn, CLKAn, CLKBn: R}_{S} &= 50 \Omega, \\ R_{L} &= 50 \Omega, \text{ C}_{L} &= 1 \text{ pF} \\ V_{I/O} &= 200 \text{ mV} + 200 \text{ mV}_{PP} \text{ (differential)} \\ \text{f} &= 100 \text{ kHz} \end{split}$	-0.4			dB
C _{OFF}	Off capacitance	V _{DD} = 1.65 V to 5.5 V OE = 0 V, V _{DD} SEL = 0 V, V _{DD} Dn, CLKn, DAn, DBn, CLKAn, CLKBn = 0 V, 0.2 V f = 1250 MHz		1.5		pF
C _{ON}	On capacitance	$\begin{aligned} & \frac{V_{DD}}{OE} = 1.65 \text{ V to } 5.5 \text{ V} \\ & OE = V_{DD} \\ & SEL = 0 \text{ V, } V_{DD} \\ & Dn, CLKn, DAn, DBn, CLKAn, CLKBn = 0 \text{ V , } 0.2 \text{ V} \\ & f = 1250 \text{ MHz} \end{aligned}$		1.5		pF

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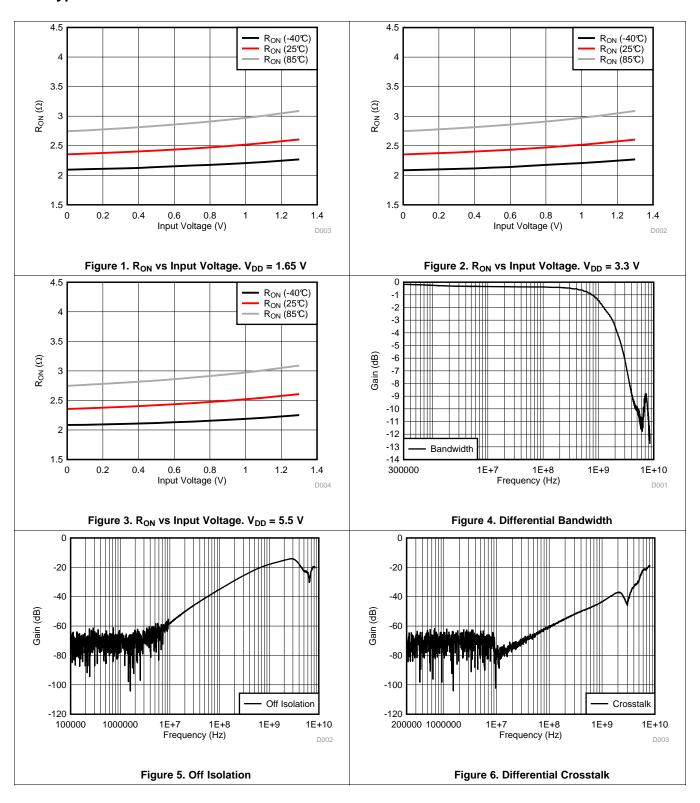
Electrical Characteristics (continued)

Over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DIGITAL CHA	ARACTERISTICS					
V _{IH}	Input logic high (SEL, OE)	$V_{I/O} = 0.6 \text{ V}, R_L = 50 \Omega, C_L = 5 \text{ pF}$	1.425		5.5	V
V_{IL}	Input logic low (SEL, OE)	$V_{I/O} = 0.6 \text{ V}, R_L = 50 \Omega, C_L = 5 \text{ pF}$	0		0.5	V
I _{IH}	Input high leakage current (SEL, OE)	$V_{I/O} = 0.6 \text{ V}, R_L = 50 \Omega, C_L = 5 \text{ pF}$	-5		5	μΑ
I _{IL}	Input low leakage current (SEL, OE)	$V_{I/O} = 0.6 \text{ V}, R_L = 50 \Omega, C_L = 5 \text{ pF}$	-5		5	μA
R _{PD}	Internal pull-down resistance on digital input pins	$V_{I/O} = 0.6 \text{ V}, R_L = 50 \Omega, C_L = 5 \text{ pF}$		6		ΜΩ
C _{SEL} , C _{OE}	Digital Input capacitance (SEL, OE)	f = 1 MHz		5		pF



6.6 Typical Characteristics

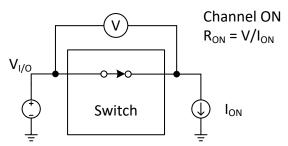


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7 Parameter Measurement Information



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Figure 7. On Resistance

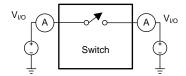


Figure 8. Off Leakage

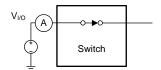
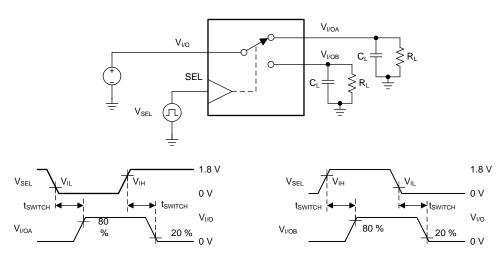


Figure 9. On Leakage

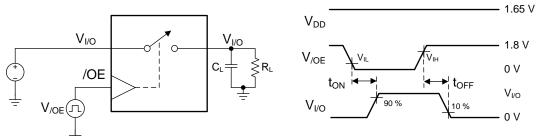


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- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_r = 3~ns$, $t_f = 3~ns$.
- (2) C_L includes probe and jig capacitance.

Figure 10. t_{SWITCH} timing

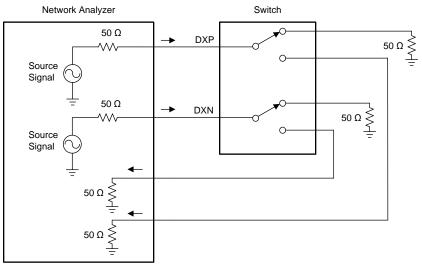




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- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_r = 3~ns$, $t_f = 3~ns$.
- (2) C_L includes probe and jig capacitance.

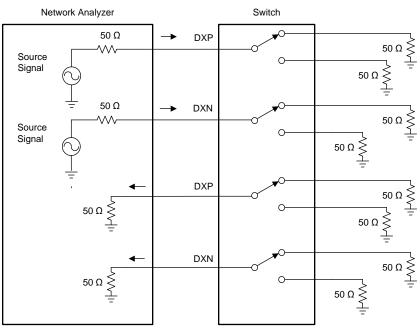
Figure 11. t_{ON} and t_{OFF} Timing for \overline{OE}



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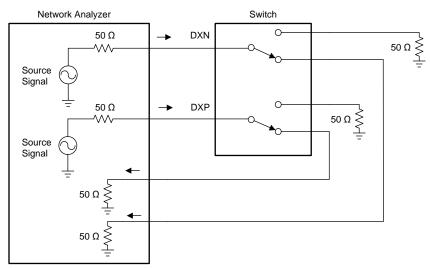
Figure 12. Off Isolation





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Figure 13. Crosstalk



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Figure 14. BW and Insertion Loss



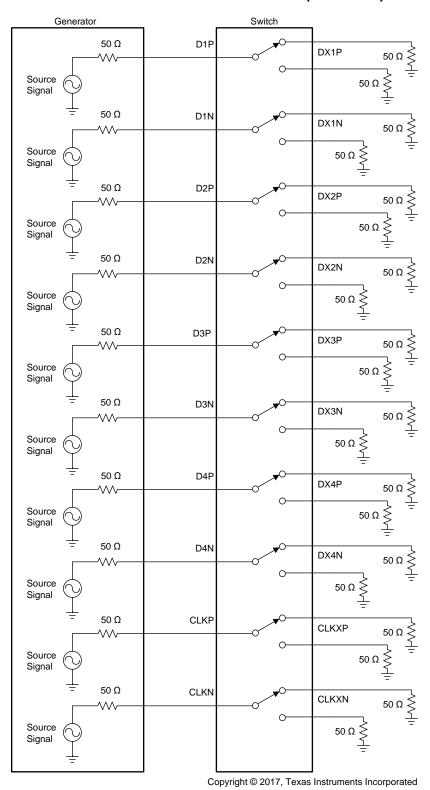
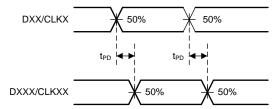


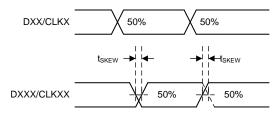
Figure 15. t_{PD} , $t_{SKEW(INTRA)}$ and t_{SKEW} Setup





- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50~\Omega$, $t_r = 100$ ps, $t_f = 100$ ps.
- (2) C_L includes probe and jig capacitance.

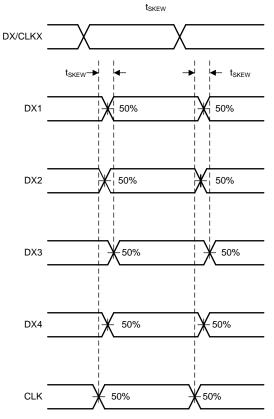
Figure 16. t_{PD}



- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50~\Omega$, $t_r = 100$ ps, $t_f = 100$ ps.
- (2) C_L includes probe and jig capacitance.

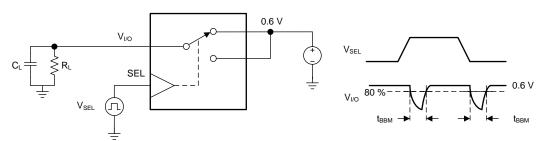
Figure 17. t_{SKEW}





- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50~\Omega$, $t_r = 100$ ps, $t_f = 100$ ps.
- (2) C_L includes probe and jig capacitance.
- (3) t_{SK(INTER)} is the max skew between all channels. Diagram exaggerates t_{SK(INTER)} to show measurement technique

Figure 18. t_{SKEW}



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- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_r = 3~ns$, $t_f = 3~ns$.
- (2) C_L includes probe and jig capacitance.

Figure 19. t_{BBM}

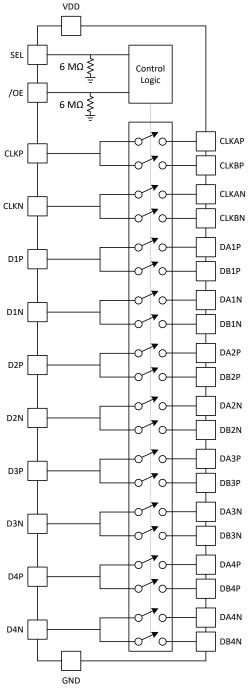


8 Detailed Description

8.1 Overview

The TS5MP645 is a high-speed 4 Data lane 2:1 MIPI Switch. The device includes 10 channels (5 differential) with 4 differential data lanes and 1 differential clock lane for D-PHY, CSI or DSI. The switch allows a single MIPI port to interface between two MIPI modules, expanding the number of potential MIPI devices that can be used within a system that is MIPI port limited.

8.2 Functional Block Diagram



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8.3 Feature Description

8.3.1 Powered-Off Protection

When the TS5MP645 is powered off (VDD = 0 V) the I/Os and digital logic pins of the device will remain in a high impedance state. The crosstalk, off-isolation, and leakage remains within the electrical specifications. This prevents errant voltages from reaching the rest of the system and maintains isolation when the system is powering up.

Figure 20 shows an example system containing a switch without powered-off protection with the following system level scenario

- 1. Subsystem A powers up and starts sending information to Subsystem B that remains unpowered.
- 2. The I/O voltage back powers the supply rail in Subsystem B.
- 3. The digital logic is back powered and turns on the switch. The signal is transmitted to Subsystem B before it is powered and damages it.

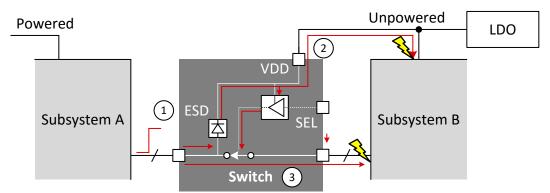


Figure 20. System Without Powered-Off Protection

With powered-off protection, the switch prevents back powering the supply and the switch remains high-impedance. Subsystem B remains protected.

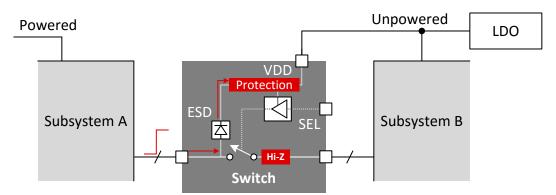


Figure 21. System With Powered-Off Protection

This features has the following system level benefits.

- Protects the system from damage.
- Prevents data from being transmitted unintentionally
- Eliminates the need for power sequencing solutions reducing BOM count and cost, simplifying system design and improving reliability.



Feature Description (continued)

8.3.2 1.8 V Logic Compatible Inputs

The TS5MP645 has 1.8 V logic compatible digital inputs for switch control. Regardless of the V_{DD} voltage the digital input thresholds remained fixed, allowing a 1.8 V processor GPIO to control the TS5MP645 without the need for an external translator. This saves both space and BOM cost.

An example setup for a system without a 1.8 V logic compatible input is shown in Figure 22. Here the supply mismatch between the process and its GPIO output and the supply to the switch require a translator.

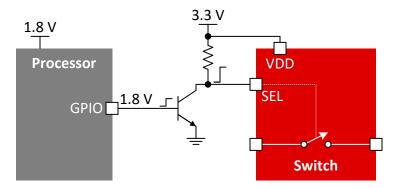


Figure 22. System Without 1.8 V Logic Compatible Inputs

With the 1.8 V logic compatibility in the TS5MP645, the translator is built in to the device so that the external components are no longer needed, simplifying the system design and overall cost.

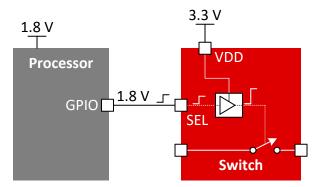


Figure 23. System With 1.8 V Logic Compatible Inputs

8.3.3 Low Power Disable Mode

The TS5MP645 has a low power mode that places all the signal paths in a high impedance state and lowers the current consumption while the device is not in use. To put the device in low power mode and disable the switch, the output enable pin \overline{OE} must be supplied with a logic high signal.



8.4 Device Functional Modes

8.4.1 Pin Functions

SEL and $\overline{\text{OE}}$ have weak 6-M Ω pulldown resistors to prevent floating input logic.

Table 1. Function Table

ŌĒ	SEL	Function
Н	X	I/O pins High-Impedance
	_	CLK(P/N) = CLKA(P/N)
_	L	Dn(P/N) = DAn(P/N)
	11	CLK(P/N) = CLKB(P/N)
_	Н	Dn(P/N) = DBn(P/N)

8.4.2 Low Power Mode

While the output enable pin \overline{OE} is supplied with a logic high the device remains in low power state. This reduces the current consumption substantially and the switches are be high impedance. The SEL pin is ignored while the \overline{OE} remains high. Upon exiting low power mode, the switch status reflects the SEL pin as seen in Table 1.

8.4.3 Switch Enabled Mode

While the output enable pin \overline{OE} is supplied with a logic low the device will remain in switch enabled mode.



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

9.2 Typical Application

Figure 24 represents a typical application of the TS5MP645 MIPI switch. The TS5MP645 is used to switch signals between multiple MIPI modules and a single MIPI port on a processor. This expands the capabilities of a single port to handle multiple MIPI modules.

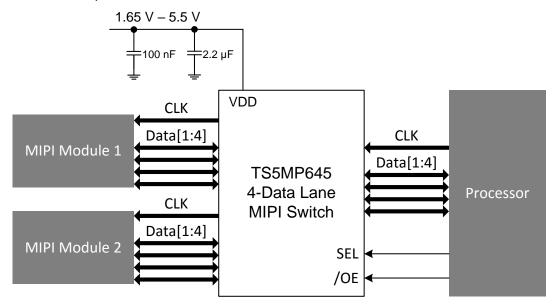


Figure 24. Typical TS5MP645 Application

9.2.1 Design Requirements

Design requirements of the MIPI standard being used must be followed. Supply pin decoupling capacitors of 2.2 μF and 100 nF are recommended for best performance. The TS5MP645 has internal 6-M Ω pulldown resistors on SEL and \overline{OE} . The pulldown on these pins ensure that the digital remains in a non-floating state during system power-up to prevent shoot through current spikes and an unknown switch status. By default the switch will power up enabled and with the A path selected until driven externally by the processor.

9.2.2 Detailed Design Procedure

The TS5MP645 can be properly operated without any external components. However, TI recommends that unused I/O signal pins be connected to ground through a 50 Ω resistor to prevent signal reflections and maintain device performance. The NC pins of the device do not require any external connections or terminations and have no connection to the rest of the device internally.

The clock and data lanes can be interchanged as necessary to facilitate the best layout possible for the application. For example the clock can be placed on the D1 channel and a data lane can be used on the CLK channel if this improves the layout. In addition the signal lines of the TS5MP645 are routed single ended on the chip die. This makes the device suitable for both differential and single-ended high-speed systems.



Typical Application (continued)

9.2.3 Application Curves

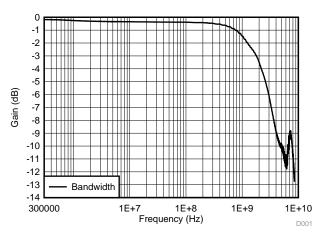


Figure 25. Differential Bandwidth

10 Power Supply Recommendations

When the TS5MP645 is powered off (V_{DD} = 0 V), the I/Os of the device remains in a high-Z state. The crosstalk, off-isolation, and leakage remain within the electrical *Specifications*. Power to the device is supplied through the VDD pin. Decoupling capacitors of 100 nF and 2.2 μ F are recommended on the supply.



11 Layout

11.1 Layout Guidelines

Place the supply de-coupling capacitors as close to the VDD and GND pin as possible. The spacing between the power traces, supply and ground, and the signal I/O lines, clock and data, should be a minimum of three times the race width of the signal I/O lines to maintain signal integrity.

The characteristic impedance of the trace(s) must match that of the receiver and transmitter to maintain signal integrity. Route the high-speed traces using a minimum amount of vias and corners. This will reduce the amount of impedance changes.

When it becomes necessary to make the traces turn 90°, use two 45° turns or an arc instead of making a single 90° turn.

Do not route high-speed traces near crystals, oscillators, external clock signals, switching regulators, mounting holes or magnetic devices.

Avoid stubs on the signal lines.

All I/O signal traces should be routed over a continuous ground plane with no interruptions. The minimum width from the edge of the trace to any break in the ground plane must be 3 times the trace width. When routing on PCB inner signal layers, the high speed traces should be between two ground planes and maintain characteristic impedance.

High speed signal traces must be length matched as much as possible to minimize skew between data and clock lines.

11.2 Layout Example

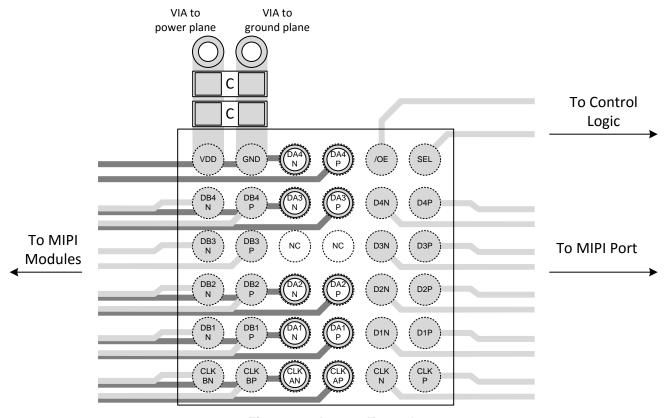


Figure 26. Layout Example



12 Device and Documentation Support

12.1 Documentation Support

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

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12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



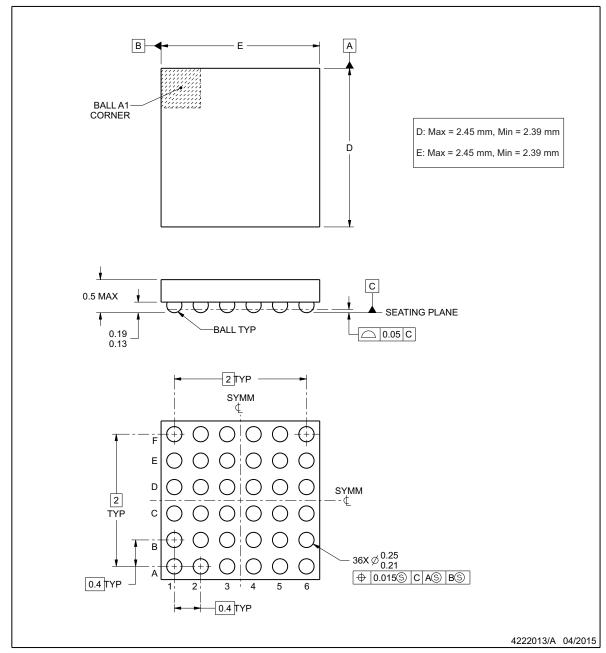
YFP0036



PACKAGE OUTLINE

DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.



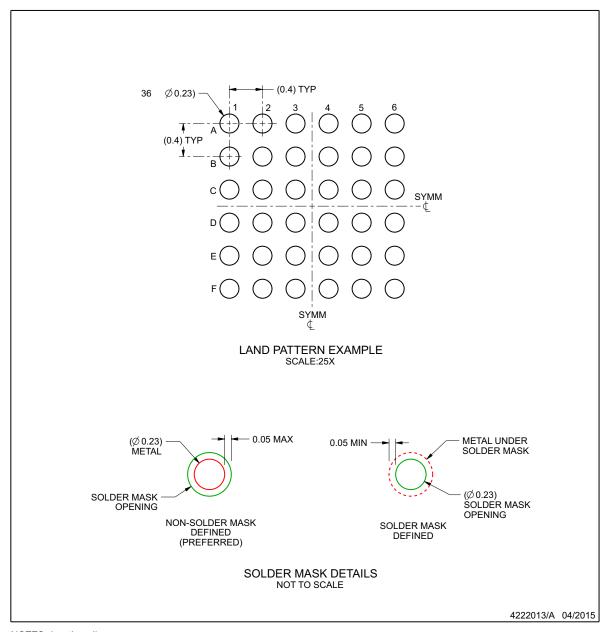


EXAMPLE BOARD LAYOUT

YFP0036

DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY



NOTES: (continued)

Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



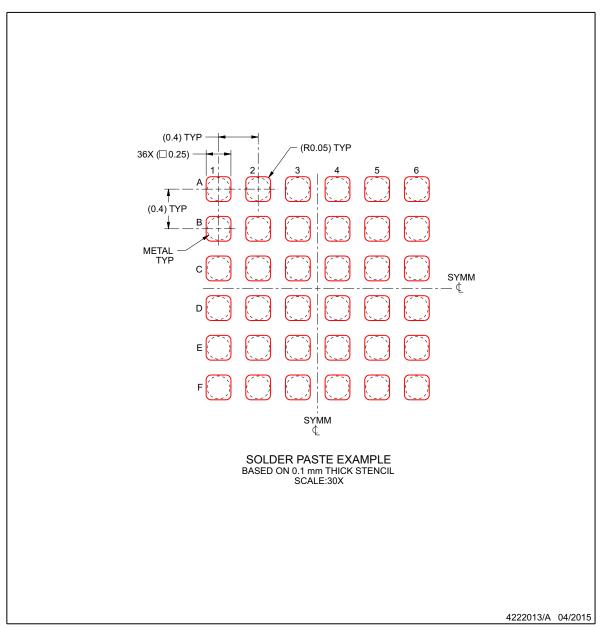


EXAMPLE STENCIL DESIGN

YFP0036

DSBGA - 0.5 mm max height

DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



www.ti.com 10-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TS5MP645NYFPR	NRND	Production	DSBGA (YFP) 36	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	TS5MP645
TS5MP645NYFPR.A	NRND	Production	DSBGA (YFP) 36	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	TS5MP645
TS5MP645YFPR	NRND	Production	DSBGA (YFP) 36	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	TS5MP645
TS5MP645YFPR.A	NRND	Production	DSBGA (YFP) 36	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	TS5MP645

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

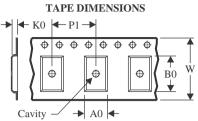
⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

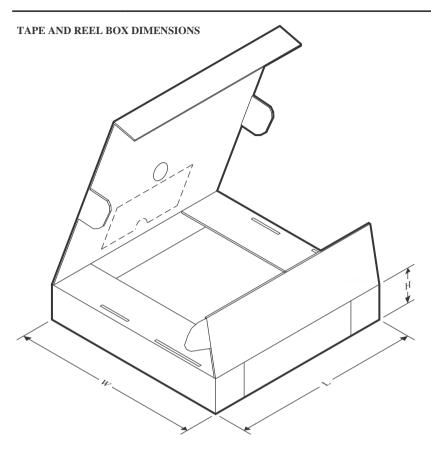


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS5MP645NYFPR	DSBGA	YFP	36	3000	180.0	8.4	2.58	2.58	0.62	4.0	8.0	Q1
TS5MP645YFPR	DSBGA	YFP	36	3000	330.0	12.4	2.58	2.58	0.62	8.0	12.0	Q1



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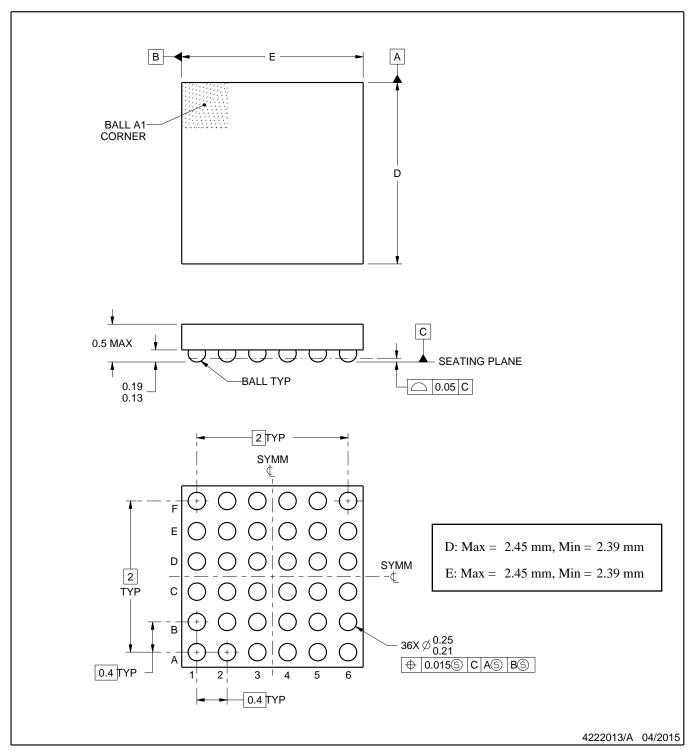


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS5MP645NYFPR	DSBGA	YFP	36	3000	182.0	182.0	20.0
TS5MP645YFPR	DSBGA	YFP	36	3000	335.0	335.0	25.0



DIE SIZE BALL GRID ARRAY

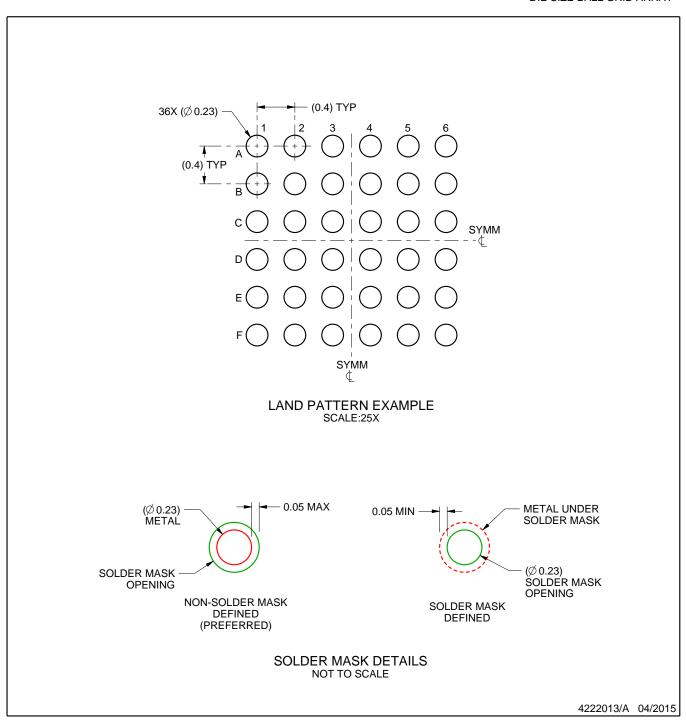


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY

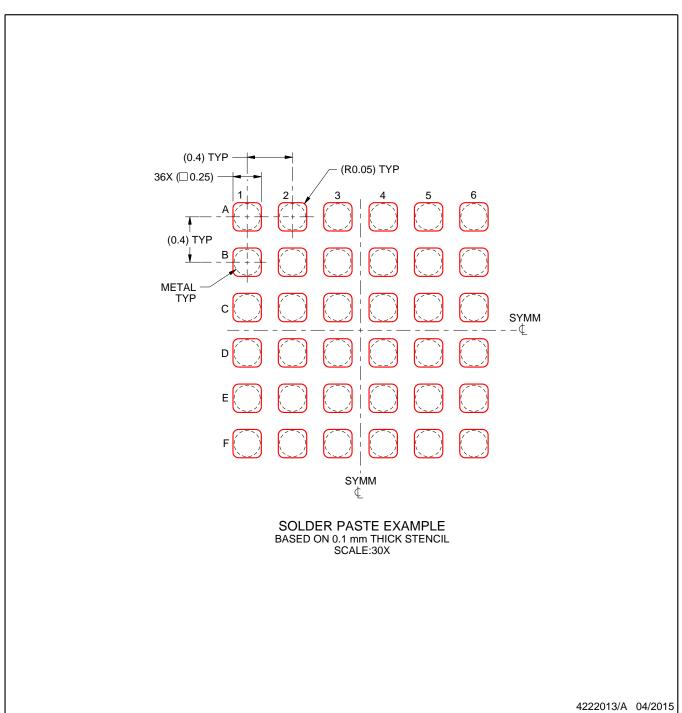


NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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